

FIG. 1A

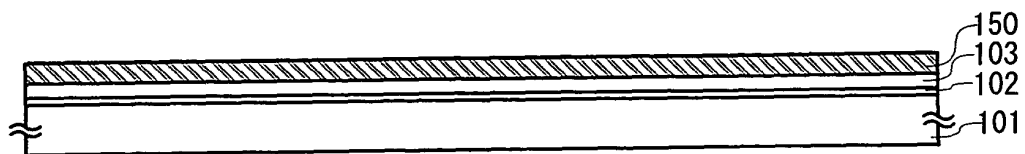


FIG. 1B

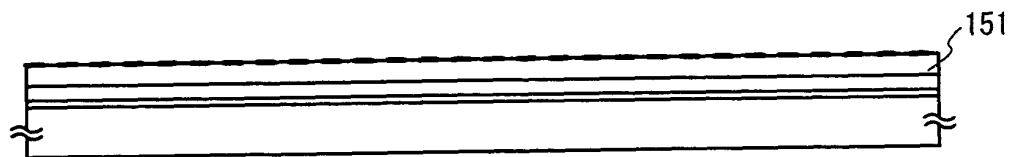


FIG. 1C

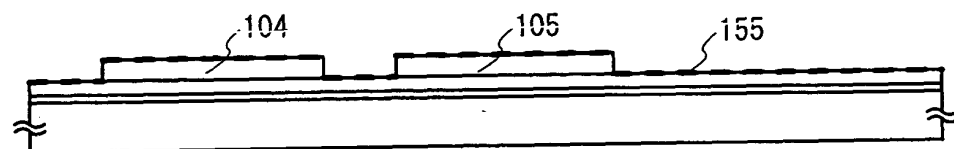


FIG. 1D

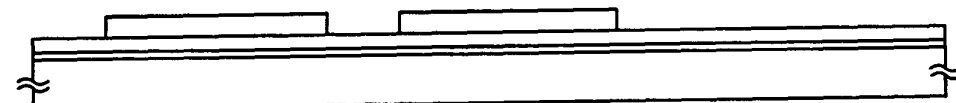


FIG. 1E

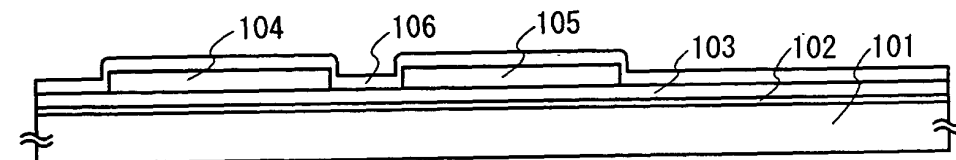
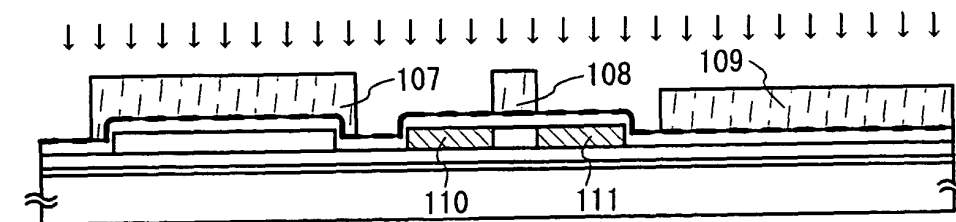


FIG. 1F



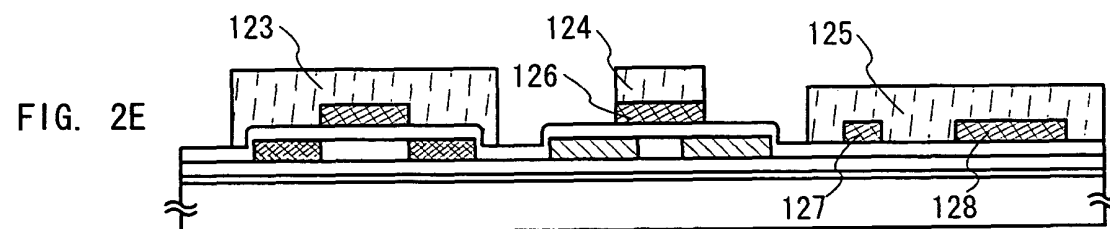
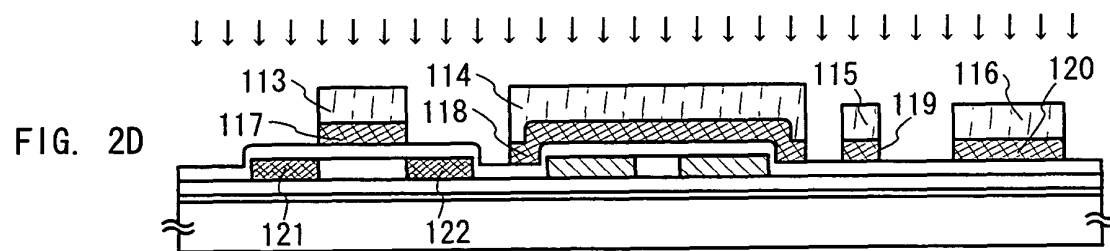
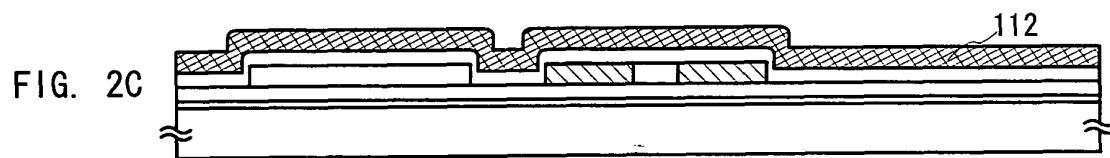
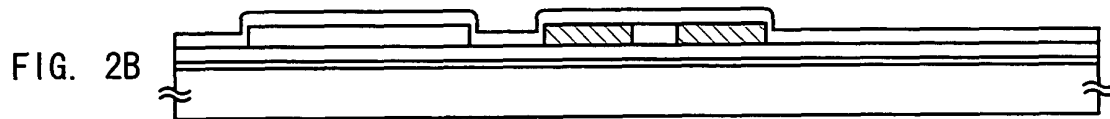
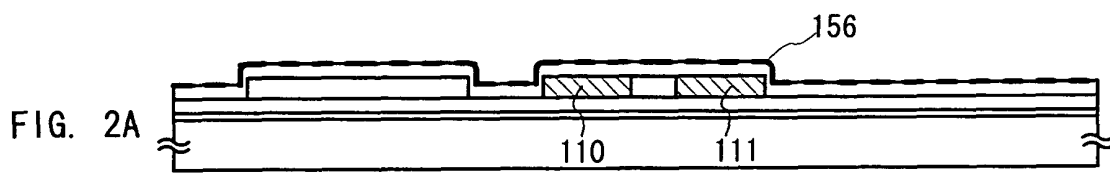


FIG. 3A

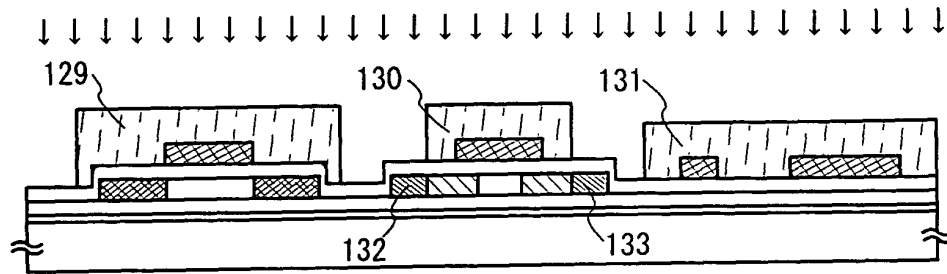


FIG. 3B

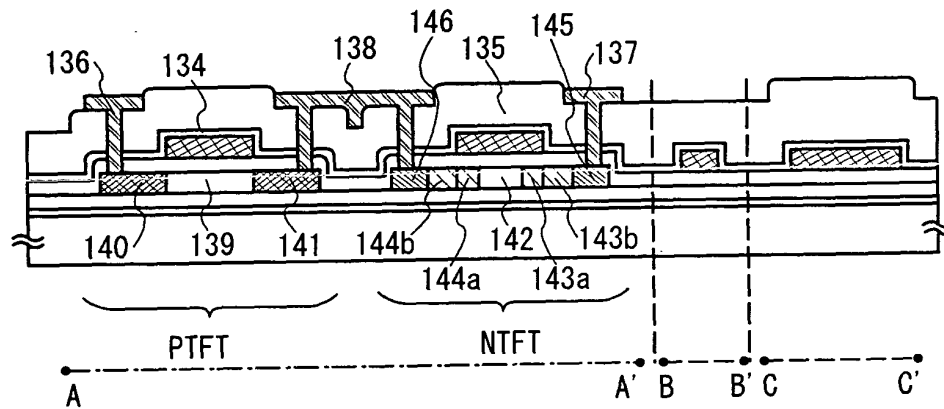
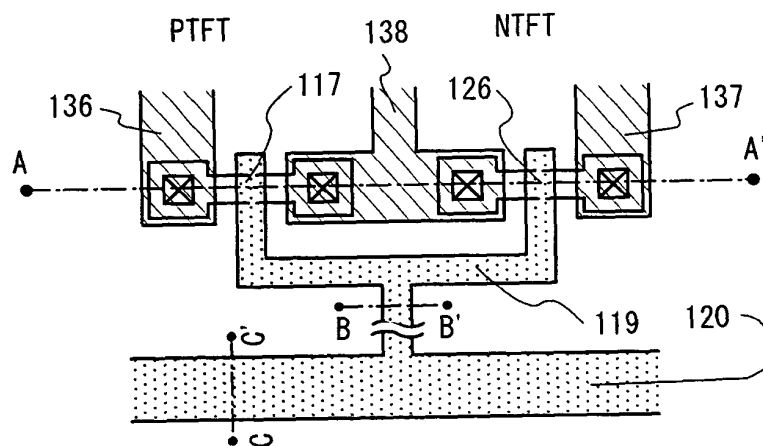


FIG. 3C



007220 222500

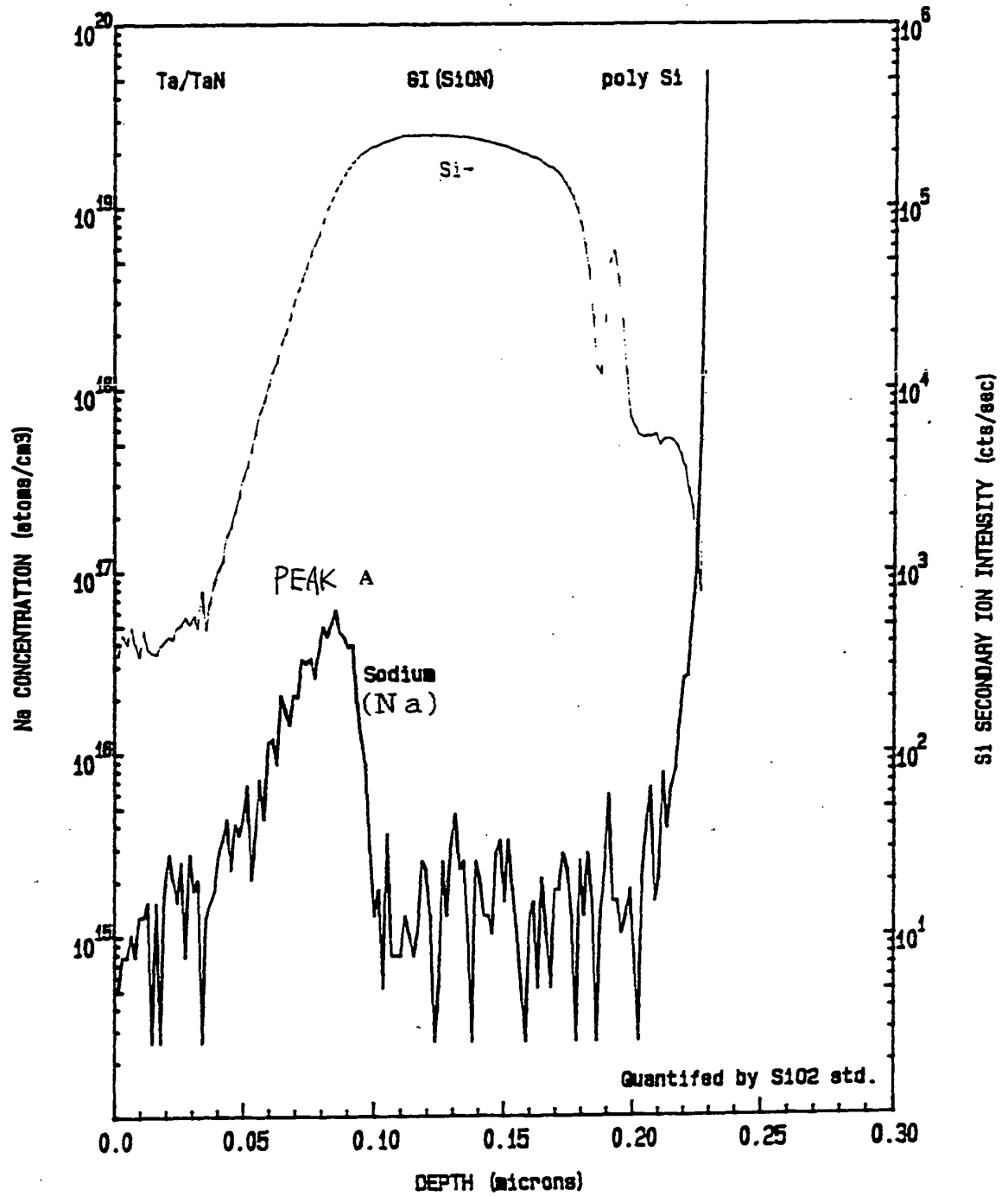


FIG.4

Na concentration (atoms/cm<sup>3</sup>)

Si secondary ion intensity (cts/sec)

DEPTH (microns)

Ta/TaN

6I (SiON)

poly Si

Si-

PEAK A

Sodium (Na)

PEAK B

Quantified by SiO<sub>2</sub> std.

FIG. 5.

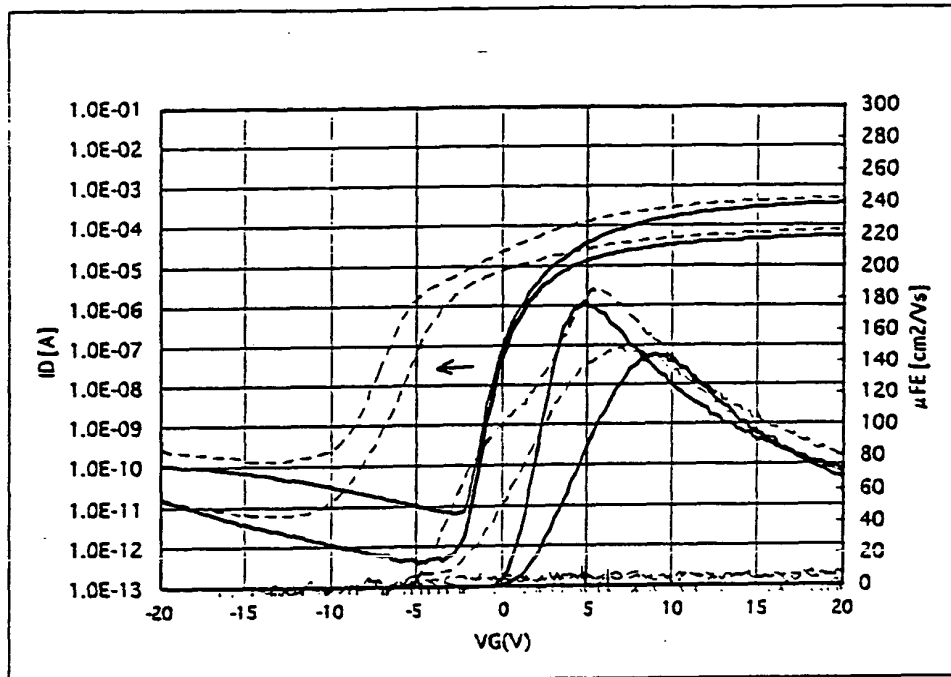


FIG. 6A

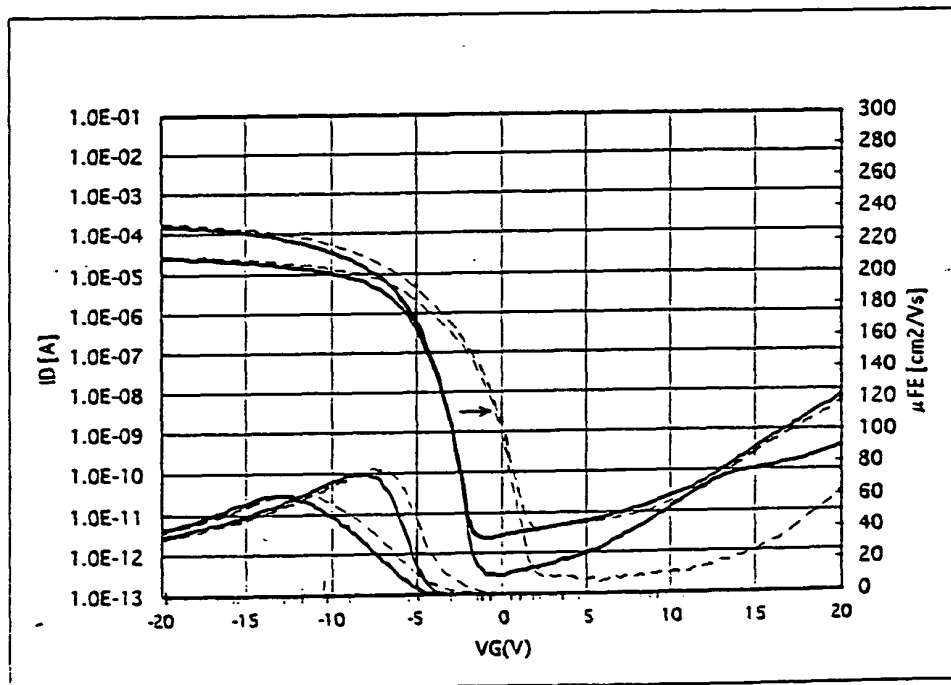


FIG. 6B

004220 2256560

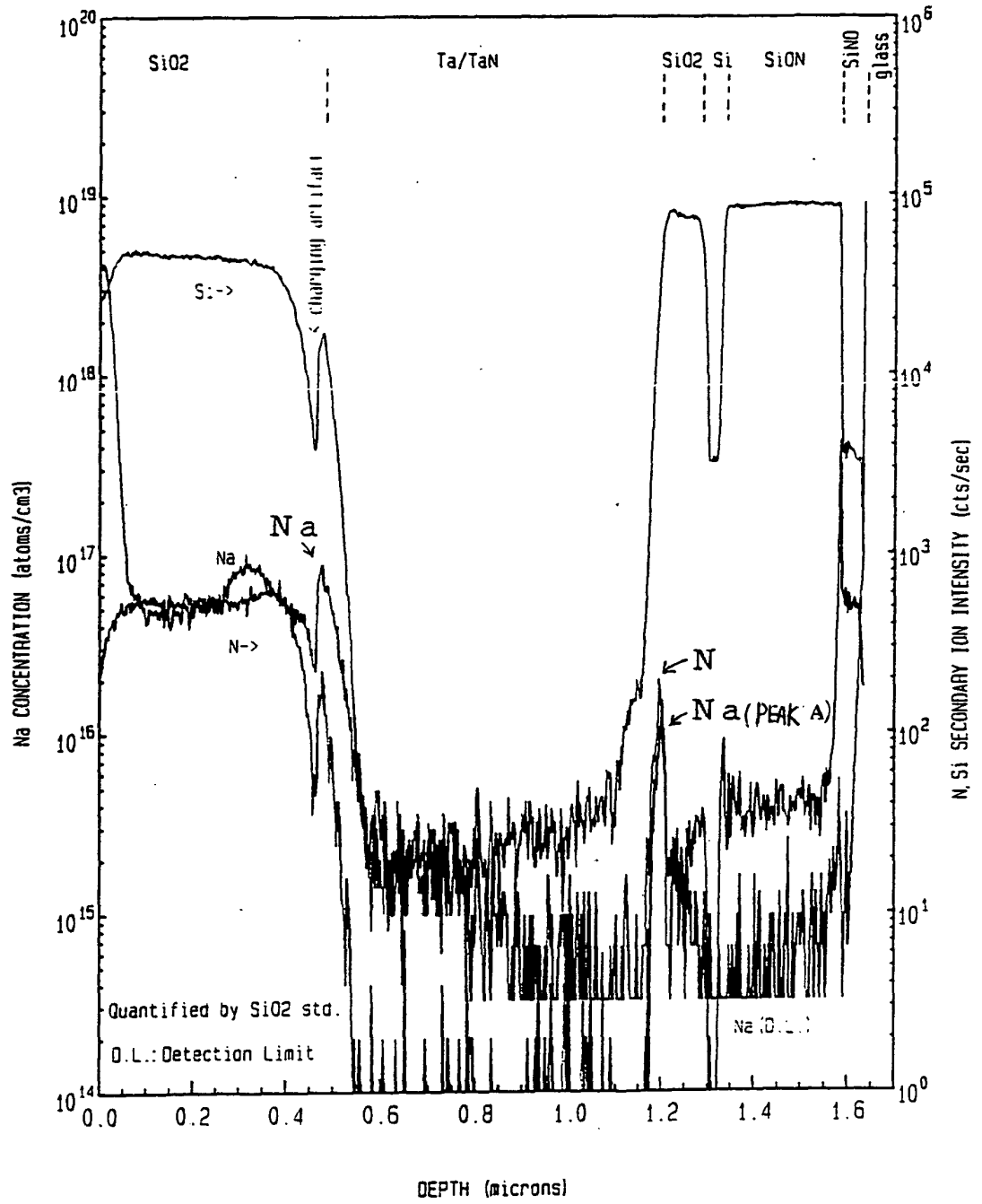
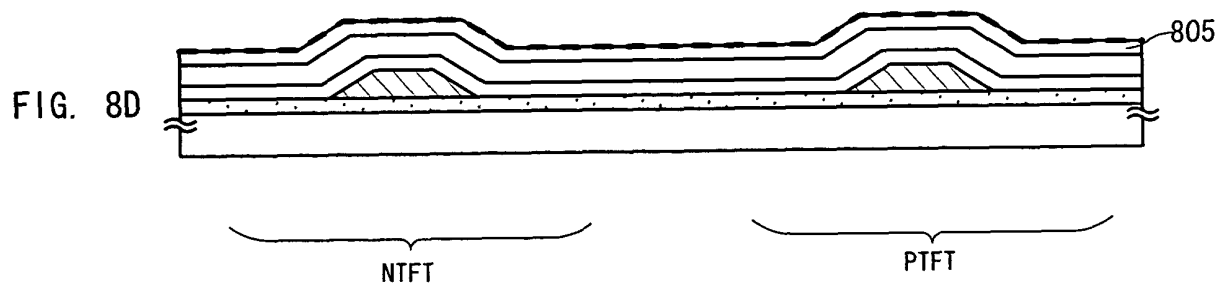
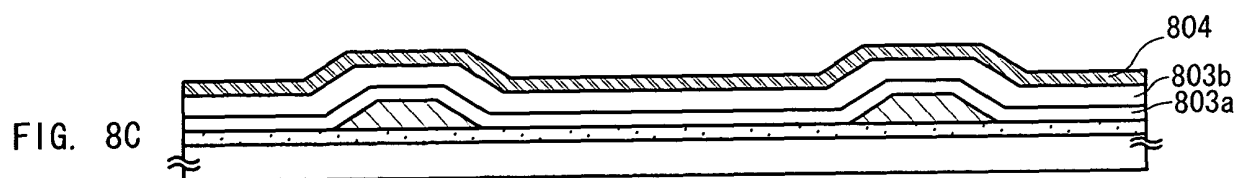
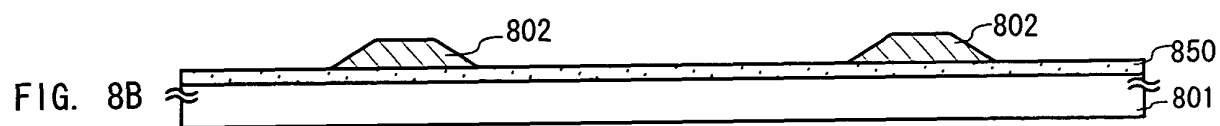
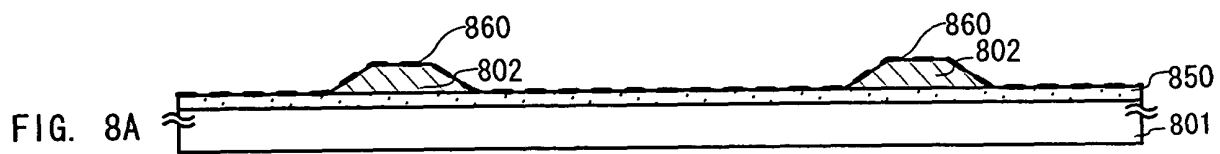
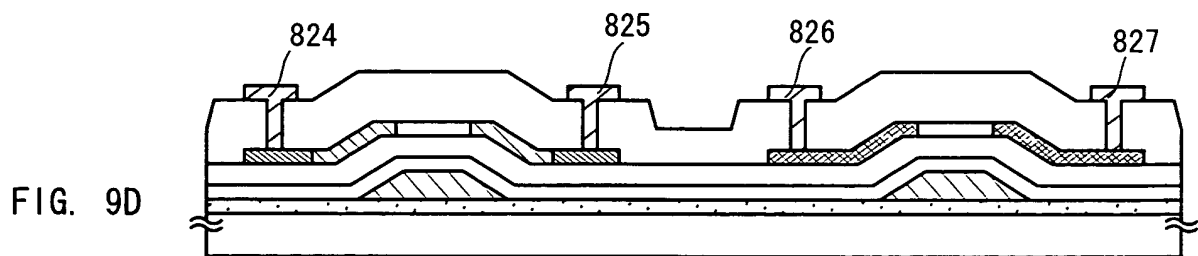
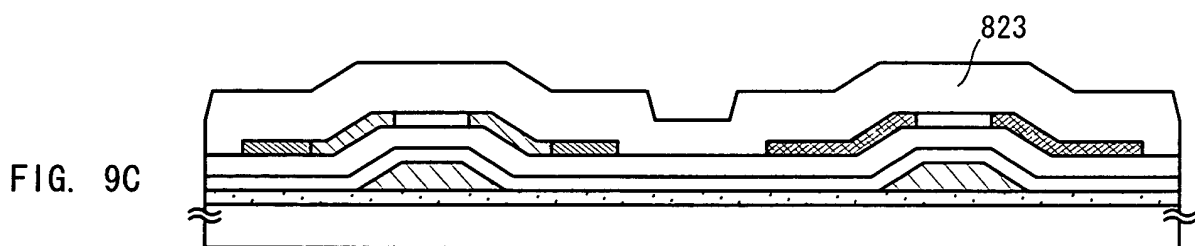
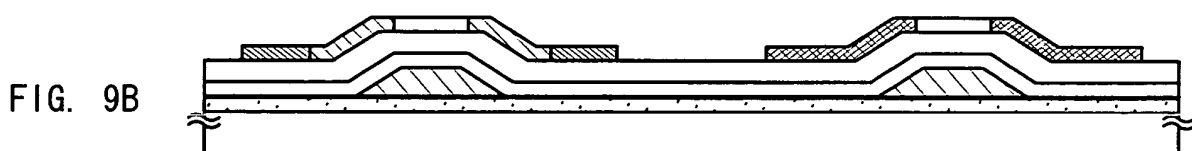
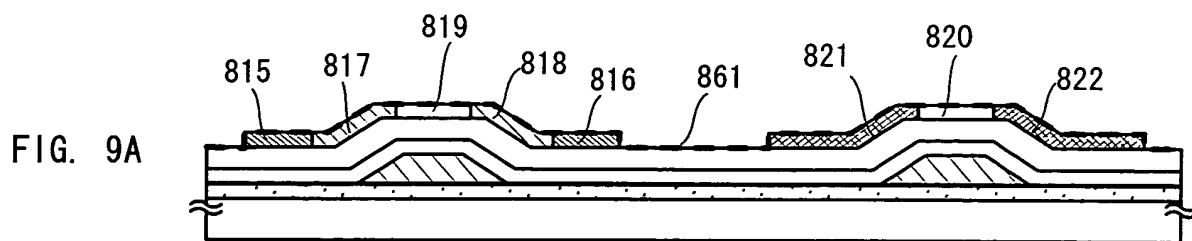


FIG. 7







NTFT

PTFT

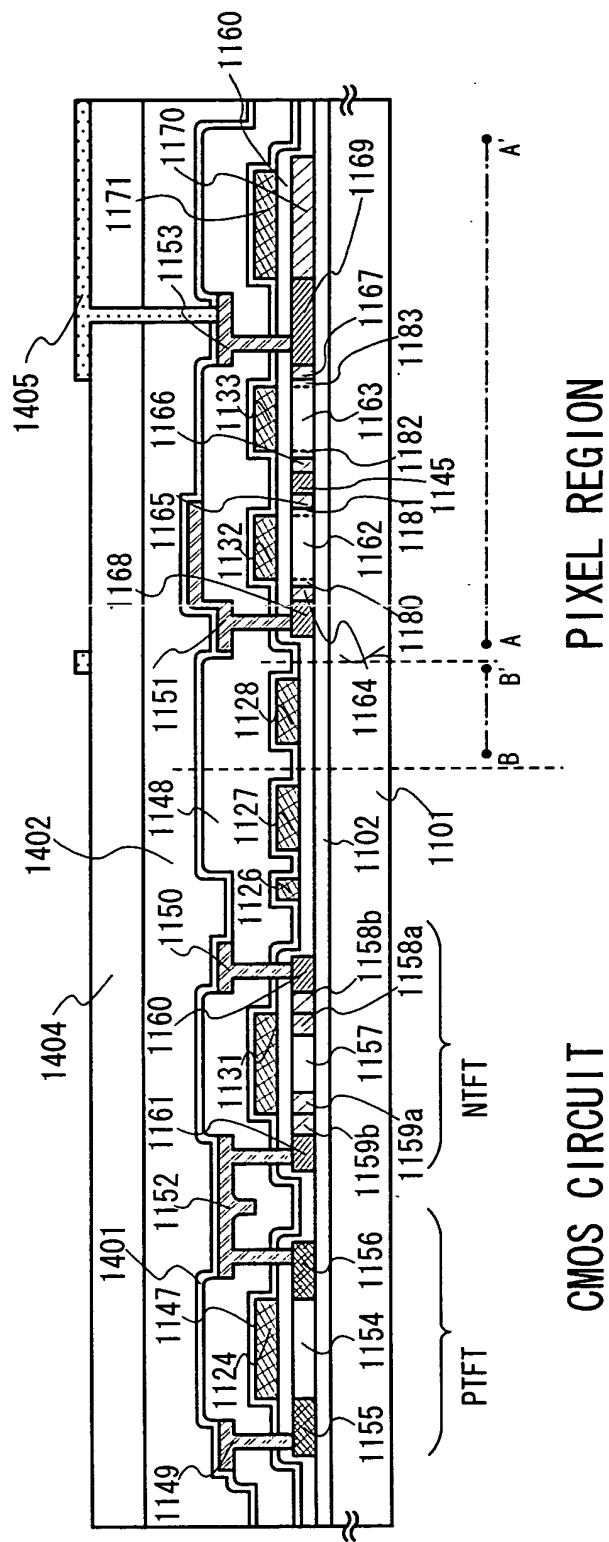


FIG. 10

This cross-sectional view shows a multi-layered structure. A central core 1705 is surrounded by a thick layer 1706. This core is further enclosed by a series of layers including 1707, 1704, and 1703. On the left side, there are vertical structural elements 1701 and 1702. Section lines A-A' and B-B' are indicated with dots and labels.

FIG. 11

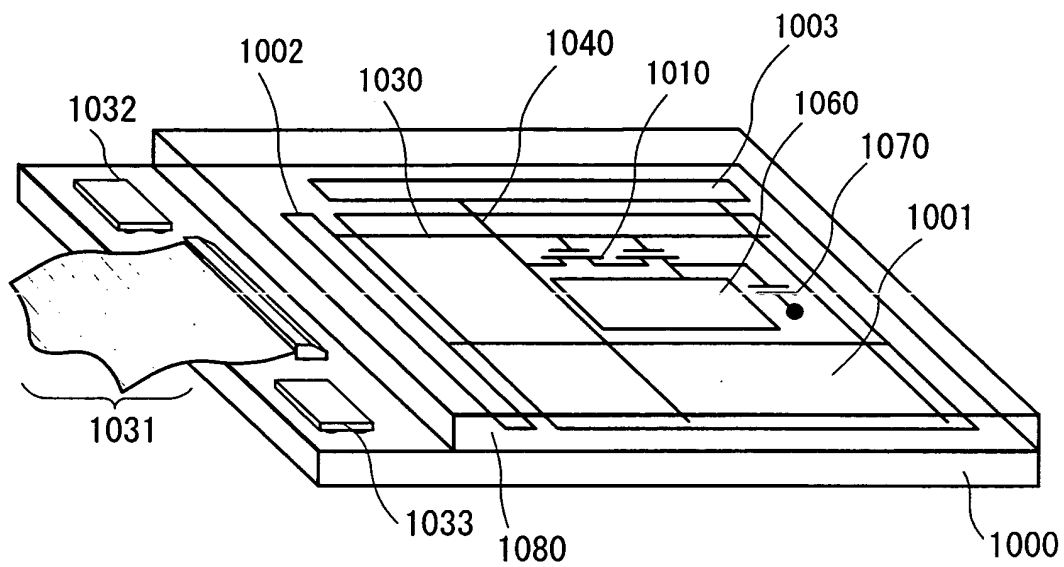


FIG. 12

83: Y-direction peripheral circuit

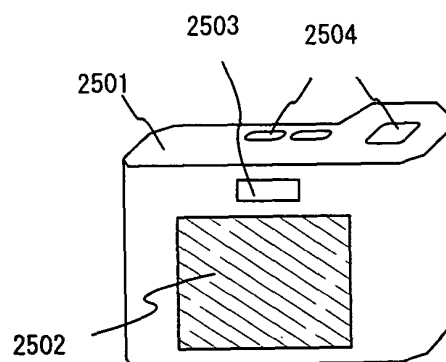
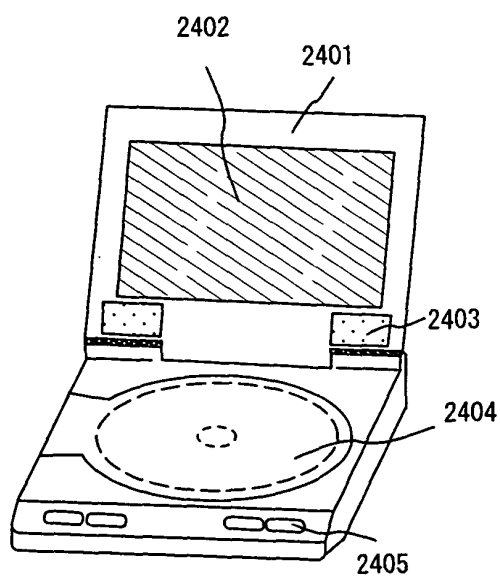
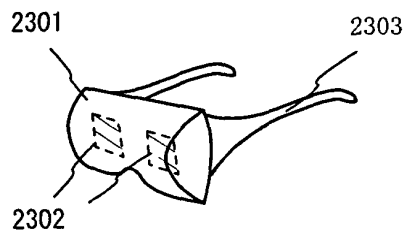
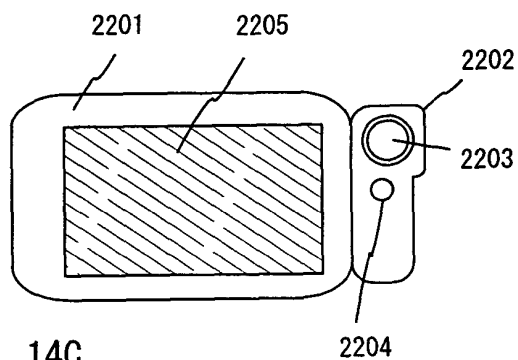
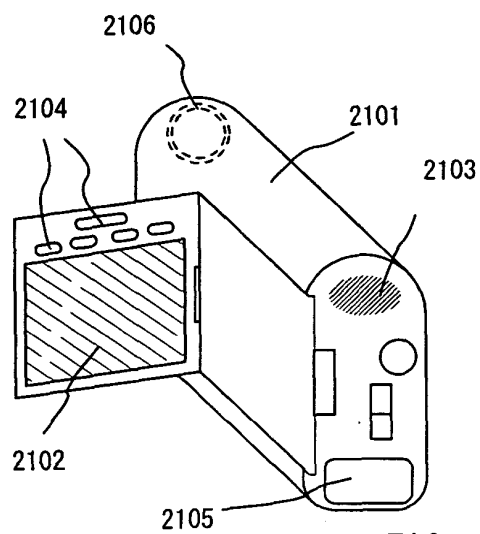
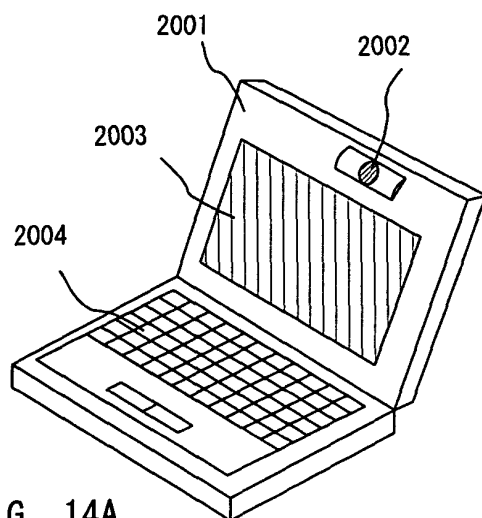
82: X-direction peripheral circuit

80a, 80b, 80c

88a, 88b, 89a, 89b

85, 86, 87

FIG. 13



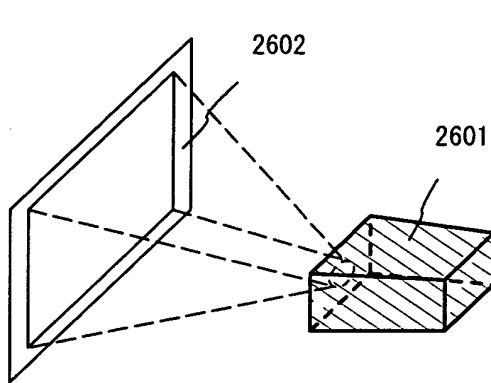


FIG. 15A

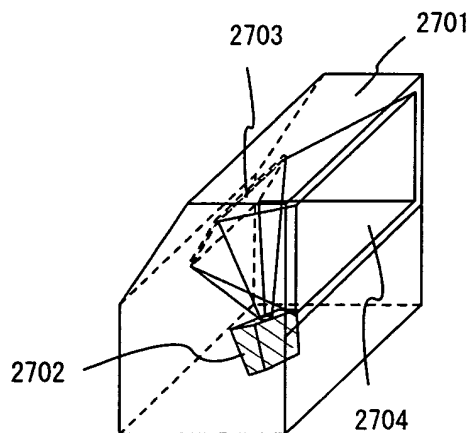


FIG. 15B

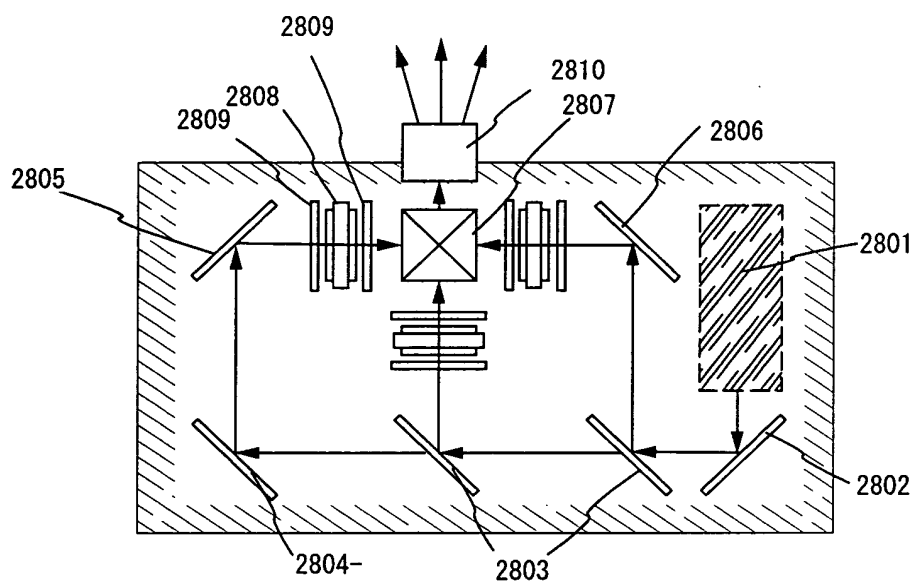


FIG. 15C

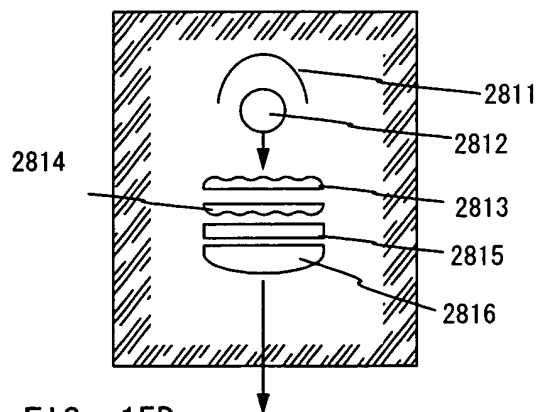


FIG. 15D

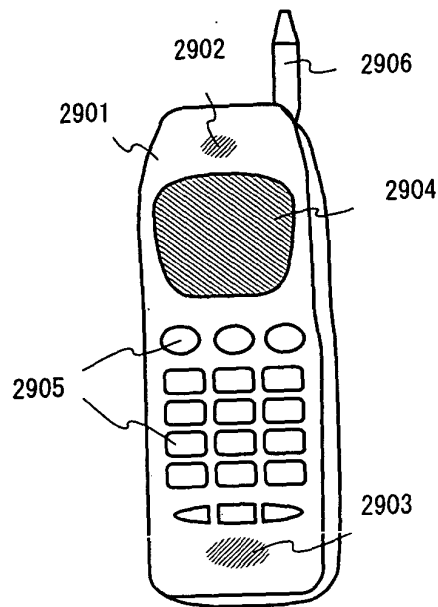


FIG. 16A

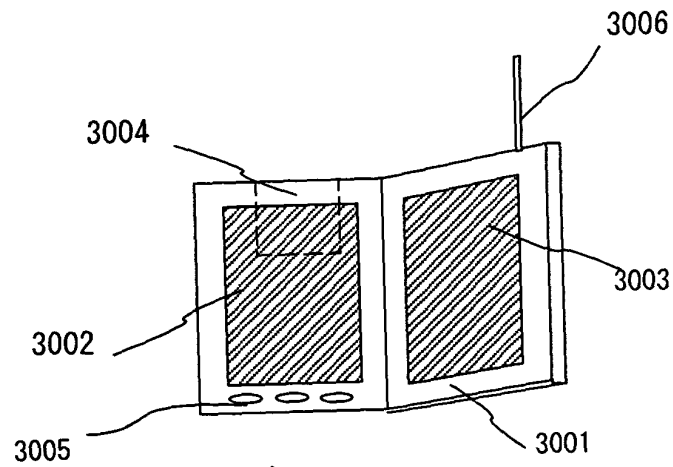


FIG. 16B

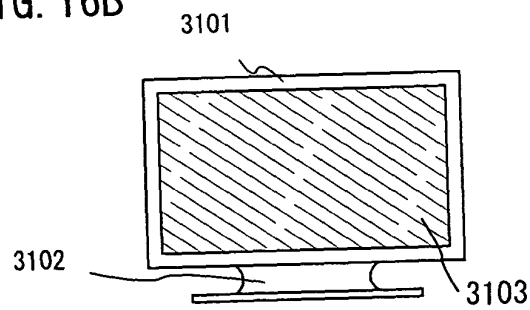


FIG. 16C



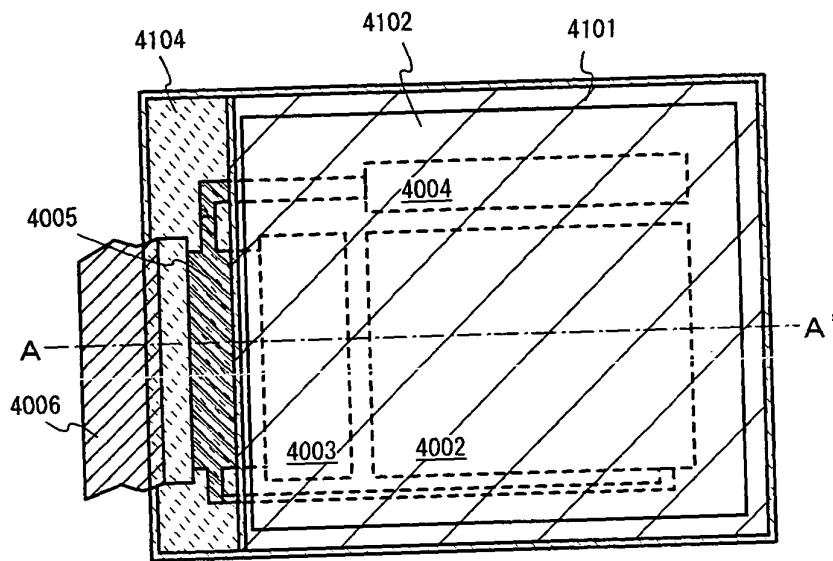


FIG. 17A

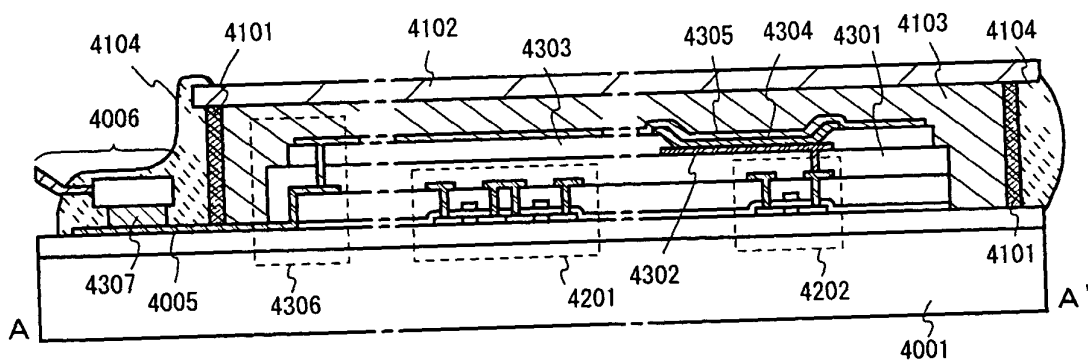


FIG. 17B

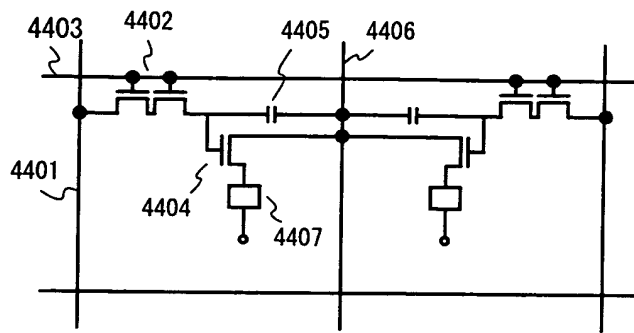


FIG. 18A

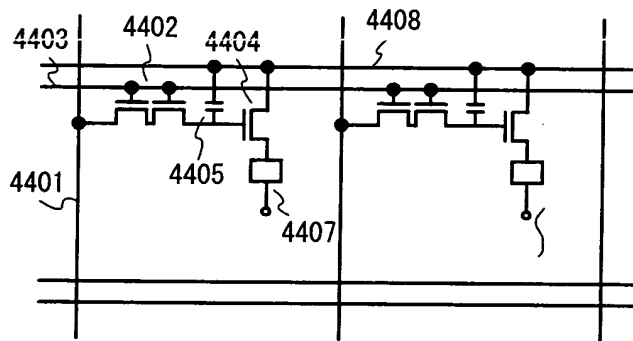


FIG. 18B

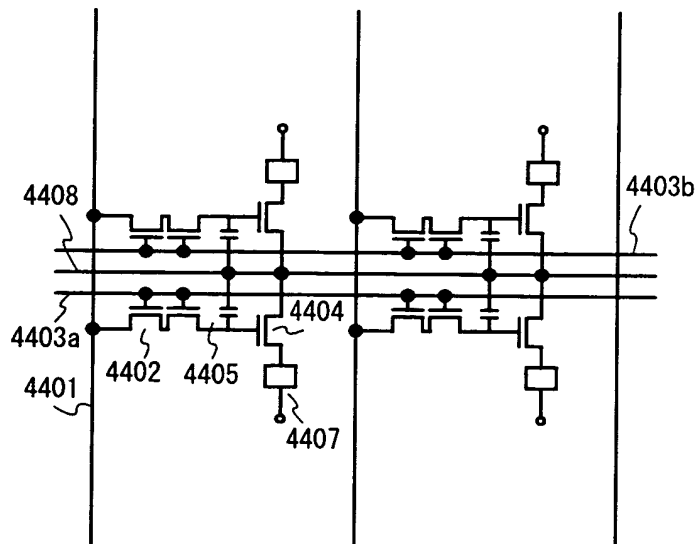


FIG. 18C